

Special Issue

Deep Learning in Medical Image Processing and Analysis

Message from the Guest Editors

Recently, deep learning (DL) techniques have revolutionized the field of medical image processing, enabling automated analysis of medical images and enhancing the accuracy and efficiency of clinical diagnosis. The use of DL in medical image processing has significantly improved the detection, classification, and segmentation of various pathological conditions, leading to improved patient outcomes. Therefore, the application of DL in medical image processing in clinical settings is becoming increasingly common.

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